

Octal buffer (3-State)**54F244****FEATURES**

- Octal bus interface
- 3-State buffer outputs sink 48mA
- 12mA source current

DESCRIPTION

The 54F244 is an octal buffer that is ideal for driving bus lines or buffer memory address registers. The outputs are all capable of sinking 48mA and sourcing up to 12mA, producing very good capacitive drive characteristics. The device features two Output Enables, \overline{OE} , each controlling four of the 3-State outputs.

FUNCTION TABLE

INPUTS		OUTPUTS	
\overline{OE}_a	I_a	\overline{OE}_b	I_b
L	L	L	L
L	H	L	H
H	X	H	X
			(Z)

H = High voltage level

L = Low voltage level

X = Don't care

(Z) = High impedance (off) state

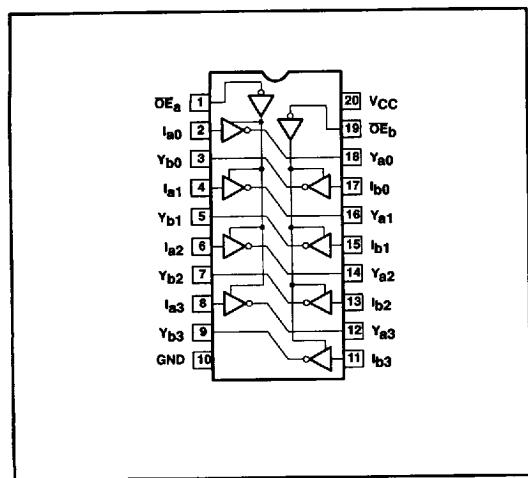
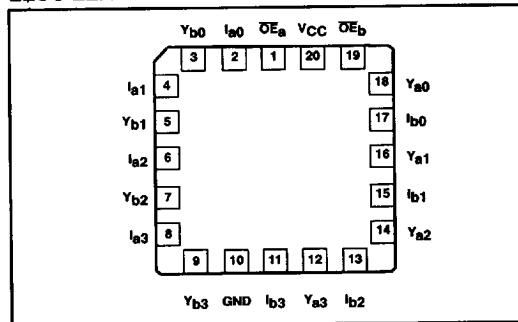
ORDERING INFORMATION

DESCRIPTION	ORDER CODE	PACKAGE DESIGNATOR*
20-Pin Ceramic DIP	54F244/BRA	GDIP1-T20
20-Pin Ceramic Flat Pack	54F244/BSA	GDFP2-F20
20-Pin Ceramic LLCC	54F244/B2A	CQCC2-N20

* MIL-STD 1835 or Appendix A of 1995 Military Data Handbook

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	54F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
\overline{OE}_a	3-State output enable input (active Low)	1.0/1.67	20 μ A/1.0mA
\overline{OE}_b	3-State output enable input (active Low)	1.0/1.67	20 μ A/1.0mA
$I_{a0} - I_{a3}, I_{b0} - I_{b3}$	Data inputs	1.0/2.67	20 μ A/1.6mA
$Y_{a0} - Y_{a3}, Y_{b0} - Y_{b3}$	Data outputs	600/80	12mA/48mA

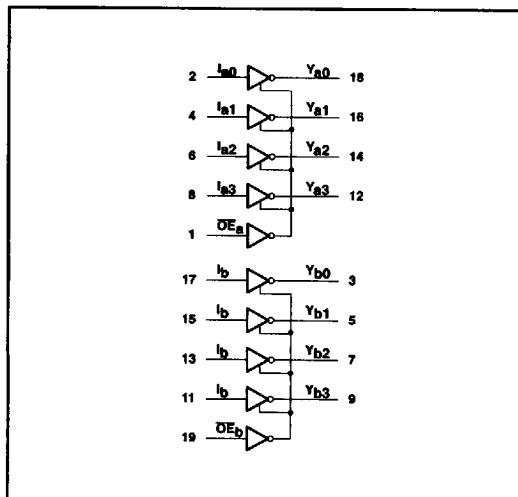
NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20 μ A in the High state and 0.6mA in the Low state**PIN CONFIGURATION****LLCC LEAD CONFIGURATION**

7110826 0085612 889 ■■■

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54F244

LOGIC SYMBOL



ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage range	-0.5 to +7.0	V
V_I	Input voltage range	-0.5 to +7.0	V
I_I	Input current range	-30 to +5	mA
V_O	Voltage applied to output in High output state range	-0.5 to V_{CC}	V
I_O	Current applied to output in Low output state	96	mA
T_{STG}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Typ	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH1}	High-level output current			-1	mA
I_{OH2}	High-level output current			-3	mA
I_{OH3}	High-level output current			-12	mA
I_{OL}	Low-level output current			48	mA
T_A	Operating free-air temperature range	-55		+125	°C

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹		LIMITS			UNIT
		Min	Typ ²	Max	Min	Typ ²	
V_{OH}	High-level output voltage	$V_{CC} = \text{Min}$,	$I_{OH1} = -1\text{mA}$	2.5			V
		$V_{IL} = \text{Max}$,	$I_{OH2} = -3\text{mA}$	2.4			V
		$V_{IH} = \text{Min}$	$I_{OH3} = -12\text{mA}$	2.0			V
V_{OL}	Low-level output voltage	$V_{CC} = \text{Min}$, $V_{IL} = \text{Max}$, $V_{IH} = \text{Min}$	$I_{OL} = \text{Max}$		0.35	0.50	V
V_{IK}	Input clamp voltage	$V_{CC} = \text{Min}$, $I_I = I_{IK}$			-0.73	-1.2	V
I_{IH2}	Input current at maximum input voltage	$V_{CC} = \text{Max}$, $V_I = 7.0\text{V}$				100	μA
I_{IH1}	High-level input current	$V_{CC} = \text{Max}$, $V_I = 2.7\text{V}$			1	20	μA
I_{IL}	Low-level input current	OE_a, OE_b	$V_{CC} = \text{Max}$, $V_I = 0.5\text{V}$		-0.7	-1.0	mA
		$I_{a0} - I_{a3}$, $I_{b0} - I_{b3}$			-0.6	-1.6	mA
I_{OZH}	Off-state output current, High-level voltage applied	$V_{CC} = \text{Max}$, $V_{IH} = \text{Min}$, $V_O = 2.7\text{V}$			2	50	μA
I_{OZL}	Off-state output current, Low-level voltage applied	$V_{CC} = \text{Max}$, $V_{IH} = \text{Min}$, $V_O = 0.5\text{V}$			-2	-50	μA
I_{OS}	Short-circuit output current ³	$V_{CC} = \text{Max}$, $V_O = 0.0\text{V}$		-100	-150	-225	mA
I_{CC}	Supply current ⁴ (total)	I_{CCH}	$V_{CC} = \text{Max}$		40	60	mA
		I_{CCL}			60	90	mA
		I_{CCZ}			60	90	mA

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS					UNIT	
			$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{pF}, R_L = 500\Omega$			$T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = +5.0\text{V} \pm 10\%$ $C_L = 50\text{pF}, R_L = 500\Omega$			
			Min	Typ	Max	Min	Max		
t_{PLH}	Propagation delay	Waveform 1	2.5	4.0	5.2	2.5	6.5	ns	
t_{PHL}	Propagation delay	Waveform 1	2.5	4.0	5.2	2.5	7.0	ns	
t_{PZH}	Enable to High	Waveform 2	2.0	4.3	6.0	2.0	7.5	ns	
t_{PZL}	Enable to Low	Waveform 3	2.0	5.0	7.0	2.0	8.5	ns	
t_{PHZ}	Disable from High	Waveform 2	2.0	3.5	6.0	2.0	7.0	ns	
t_{PLZ}	Disable from Low	Waveform 3	2.0	4.0	6.0	2.0	7.5	ns	

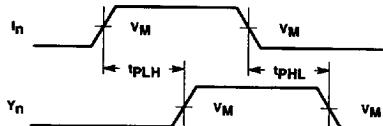
NOTES:

- For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions for the applicable type and functional table for operating mode.
- All typical values are at $V_{CC} = 5\text{V}$, $T_A = 25^\circ\text{C}$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
- I_{CC} is measured with outputs open.

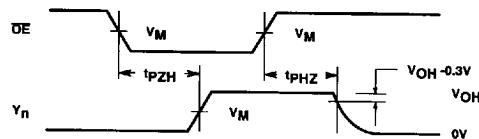
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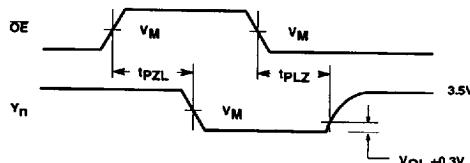
AC WAVEFORMS



Waveform 1. For Non-Inverting Outputs



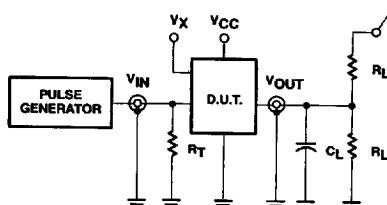
Waveform 2. 3-State Output Enable Time to High Level and Output Disable Time from High Level



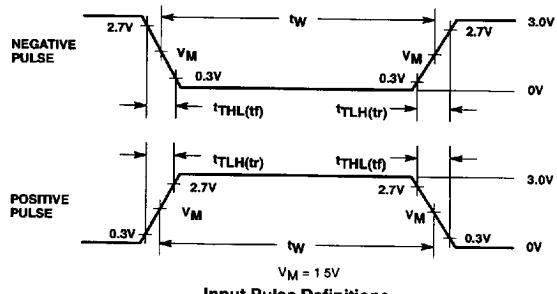
Waveform 3. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

NOTE: For all waveforms, $V_M = 1.5V$

TEST CIRCUIT AND WAVEFORM



Test Circuit for 3-State Outputs



Input Pulse Definitions

SWITCH POSITION

TEST	SWITCH
t_{PLZ} , t_{PZL} , All other	closed closed open

INPUT PULSE CHARACTERISTICS				
Family	Rep. Rate	Pulse Width	t_{TLH}	t_{THL}
54F	1MHz	500ns	$\leq 2.5ns$	$\leq 2.5ns$

DEFINITIONS:

 R_L = Load Resistor; see AC Characteristics for value. C_L = Load capacitance includes jig and probe capacitance; see AC Characteristics for value. R_T = Termination resistance should be equal to Z_{OUT} of pulse generators. V_X = Unclocked pins must be held at: $\leq 0.8V$; $\geq 2.7V$ or open per Function Table.